

AOK53S60

600V 53A aMOS TM Power Transistor

General Description

The AOK53S60 has been fabricated using the advanced $\alpha \text{MOS}^{\text{TM}}$ high voltage process that is designed to deliver high levels of performance and robustness in switching applications.

By providing low $R_{DS(on)}$, Q_g and E_{OSS} along with guaranteed avalanche capability this part can be adopted quickly into new and existing offline power supply designs.

Product Summary

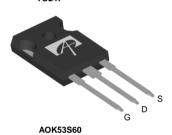
 $\begin{array}{lll} V_{DS} @ T_{j,max} & 700V \\ I_{DM} & 215A \\ R_{DS(ON),max} & 0.07\Omega \\ Q_{g,typ} & 59nC \\ E_{oss} @ 400V & 15\mu J \end{array}$

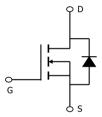
100% UIS Tested 100% R_q Tested





TO247





Orderable Part Number Package Type Form Minimum Order Quantity

AOK53S60		TO-247	Tube	240	
Absolute Maximum	Ratings T _A =25°C unles	s otherwise i	noted		
Parameter		Symbol	AOK53S60	Units	
Drain-Source Voltage		V_{DS}	600	V	
Gate-Source Voltage		V_{GS}	±30	V	
Continuous Drain Current	T _C =25°C		53		
	T _C =100°C	I _D	33	A	
Pulsed Drain Current ^C		I _{DM}	215		
Avalanche Current ^C		I _{AR}	9.5	A	
Repetitive avalanche energy ^C		E _{AR}	45	mJ	
Single pulsed avalanche energy ^G		E _{AS}	1688	mJ	
Power Dissipation ^B	T _C =25°C	— P _D	520	W	
	Derate above 25°C		4.2	W/°C	
MOSFET dv/dt ruggedness		dv/dt	100	V/ns	
Peak diode recovery dv/dt			20	V/115	
Junction and Storage Temperature Range		T_J , T_{STG}	-55 to 150	°C	
Maximum lead tempe	rature for soldering				
purpose, 1/8" from case for 5 seconds J		TL	300	°C	
Thermal Characteris	stics				
Parameter		Symbol	AOK53S60	Units	
Maximum Junction-to-Ambient A,D		$R_{\theta JA}$	40	°C/W	
Maximum Case-to-sink ^A		$R_{\theta CS}$	0.5	°C/W	
Maximum Junction-to-Case		$R_{\theta JC}$	0.24	°C/W	



Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
STATIC I	PARAMETERS					
BV _{DSS}	Drain Course Brookdown Voltage	I_D =250 μ A, V_{GS} =0V, T_J =25°C	600	-	-	
	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V, T _J =150°C	650	700	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =600V, V _{GS} =0V	-	-	1	۸
		V _{DS} =480V, T _J =150°C	-	10	-	μА
I _{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±30V	-	-	±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} =5 V , I_D =250 μ A	2.5	3.2	3.8	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V_{GS} =10V, I_{D} =26.5A, T_{J} =25°C	-	0.058	0.07	Ω
		V _{GS} =10V, I _D =26.5A, T _J =150°C	-	0.155	0.185	Ω
V_{SD}	Diode Forward Voltage	I _S =26.5A,V _{GS} =0V, T _J =25°C	-	0.84	-	V
I _S	Maximum Body-Diode Continuous Current			-	53	Α
I _{SM}	Maximum Body-Diode Pulsed Current			-	215	Α
DYNAMI	PARAMETERS		-			
C _{iss}	Input Capacitance	V 0V V 400V 5 4MU-	-	3034	-	pF
C _{oss}	Output Capacitance	V_{GS} =0V, V_{DS} =100V, f=1MHz	-	222	-	pF
C _{o(er)}	Effective output capacitance, energy related H	VCS 0V V 0 to 490V f 4MHz	-	170	-	pF
C _{o(tr)}	Effective output capacitance, time related ¹	VGS=0V, V _{DS} =0 to 480V, f=1MHz	-	524	-	pF
C _{rss}	Reverse Transfer Capacitance	VGS=0V, V _{DS} =100V, f=1MHz	-	3	-	pF
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz	-	1.8	-	Ω
SWITCH	NG PARAMETERS			•	•	
Q_g	Total Gate Charge		-	59	-	nC
Q_{gs}	Gate Source Charge	V _{GS} =10V, V _{DS} =480V, I _D =26.5A	-	17	-	nC
Q_{gd}	Gate Drain Charge	1	-	19	-	nC
t _{D(on)}	Turn-On DelayTime		-	48	-	ns
t _r	Turn-On Rise Time	V _{GS} =10V, V _{DS} =400V, I _D =26.5A,	-	102	-	ns
t _{D(off)}	Turn-Off DelayTime	$R_G=25\Omega$	-	215	-	ns
t _f	Turn-Off Fall Time	1	-	122	-	ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =26.5A,dI/dt=100A/μs,V _{DS} =400V	-	664	-	ns
I _{rm}	Peak Reverse Recovery Current	I _F =26.5A,dI/dt=100A/μs,V _{DS} =400V	-	36	-	Α
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =26.5A,dI/dt=100A/μs,V _{DS} =400V	-	14	_	μС

- A. The value of R $_{\rm BJA}$ is measured with the device in a still air environment with T $_{\rm A}$ =25 $^{\circ}$ C.
- B. The power dissipation P_D is based on T_{JIMAXI}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C, Ratings are based on low frequency and duty cycles to keep initial
- D. The R BLA is the sum of the thermal impedance from junction to case R BLC and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.
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 F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.

 G. L=60mH, I_{AS}=7.5A, V_{DD}=150V, Starting T_J=25° C

 H. C_{o(ef)} is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{(BR)DSS}.

 I. C_{o(tr)} is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{(BR)DSS}.

 J. Wavesoldering only allowed at leads.

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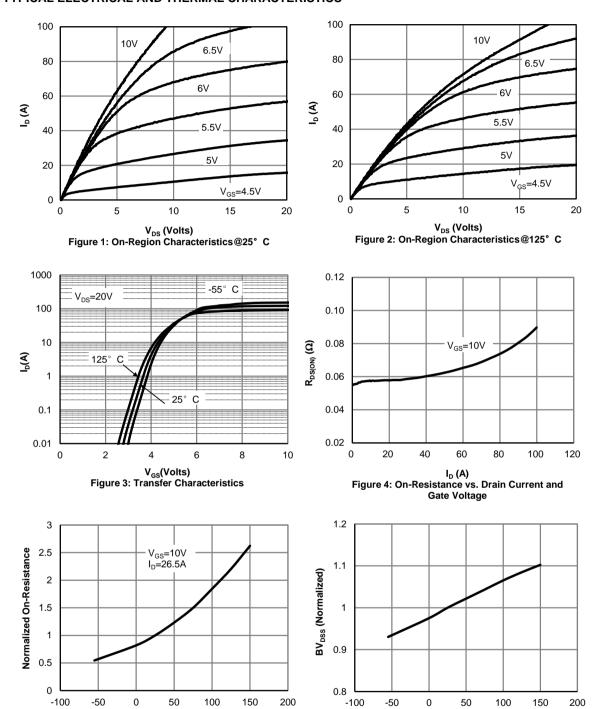
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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

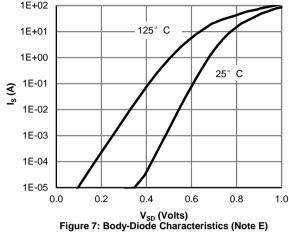
Temperature (°C)
Figure 5: On-Resistance vs. Junction Temperature

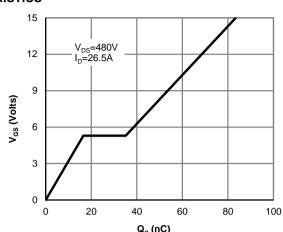


 $\rm T_{J}\left(^{o}C\right)$ Figure 6: Break Down vs. Junction Temperature

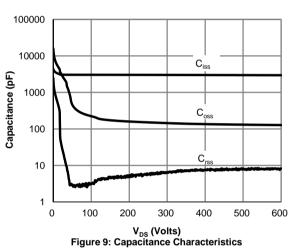


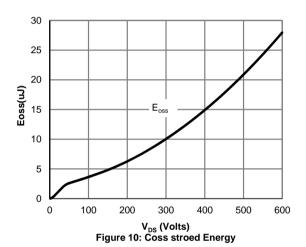
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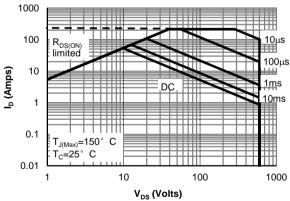




 ${\bf Q_g}$ (nC) Figure 8: Gate-Charge Characteristics



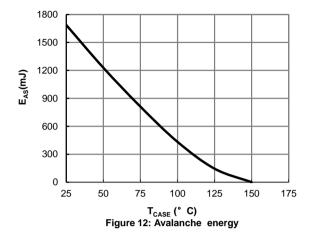


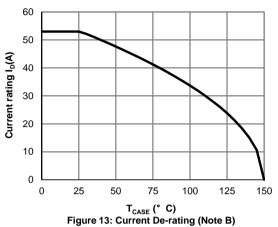


V_{DS} (Volts)
Figure 11: Maximum Forward Biased Safe
Operating Area for AOK53S60 (Note F)



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





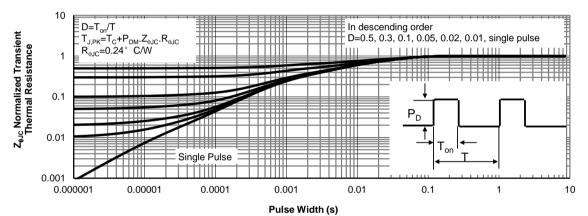
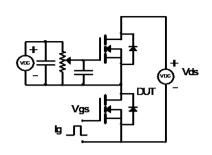
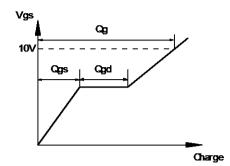


Figure 14: Normalized Maximum Transient Thermal Impedance for AOK53S60 (Note F)

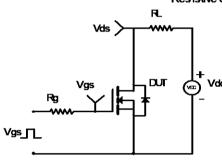


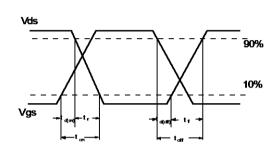
Gate Charge Test Circuit & Waveform



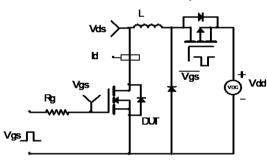


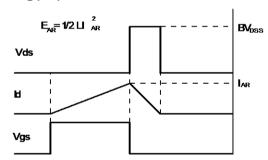
Resistive Switching Test Circuit & Waveforms





Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

